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FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
SAF	0 562 136	09/29/93	EP			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

STP	Patent Abstracts of Japan, Vol. 14, No. 535, 1990, JP 2-223531, November 26, 1990.
STP	Patent Abstracts of Japan, Vol. 13, No. 339, 1989, JP 1-117780, July 31, 1989.
EXAMINER	DATE CONSIDERED
Shannon F. Lee	3/5/01

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